

Form PTO-1449 U.S. DEPARTMENT OF COMMERCE
(REV. 7-80) PATENT AND TRADEMARK OFFICE

Atty. Docket No.
NL 000625

Serial No.

Applicant

MARTIN HILLEBRAND BLEES ET AL.

Filing Date
CONCURRENTLY

Group

INFORMATION DISCLOSURE CITATION
(Use several sheets if necessary)

U.S. PATENT DOCUMENTS

Ex. Int.		Document Number	Date	Name	Class	Sub- class	Filing Date If Approp.
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Sub- class	Trans.	
							Yes	No
	AG							
	AH							
	AI							
	AJ							
	AK							

OTHER (Including Author, Title, Date, Pertinent Pages, Etc.)

IC	AL	"Contact-Inking for Microcontact Printing of Alkanethiols on Gold" by Laurent Libiouille, Alexander Bietsch, Heinz Schmid, Bruno Michel, and Emmanuel Delamarche in Langmuir 1998, 15, 300-304.
IC	AM	"Soft Lithography by Younan Xia and George M. Whitesides, in Angew. Chem. Int. Ed., 1998, 37, pp. 550-575.
	AN	

Examiner

Date Considered 12/10/02

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP Draw line through citation if not in conformance and not considered. Include a copy this form with next communication to applicant.

JC986 U.S. PTO
09/990435
11/21/01

Form PTO-1449 U.S. DEPARTMENT OF COMMERCE
(REV. 7-80) PATENT AND TRADEMARK OFFICEAtty. Docket No.
NL000625Serial No.
09/990,435Applicant
Martin Hillebrand Blee, et.al.Filing
11/21/2001Group
2854**INFORMATION DISCLOSURE CITATION**
(Use several sheets if necessary)**U.S. PATENT DOCUMENTS**

Ex. Int		Document Number	Date	Name	Class	Sub-class	Filing Date If Approp.
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Sub-class	Trans.
							Yes No
<i>See</i>	AG	0 7 2 1 4 8 8 3 A	08/15/1995	Japan (Abstract)	B41K	1/50	
<i>See</i>	AH	0 0 2 2 1 5 4 1 0	01/19/1999	Switzerland			
	AI						
	AJ						
	AK						

OTHER (Including Author, Title, Date, Pertinent Pages, Etc.)

AL	
AM	
AN	

Examiner

Date Considered 12/10/02

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP
Draw line through citation if not in conformance and not considered. Include a copy
this form with next communication to applicant.